



Product Change Notification / JAON-23VTYQ024

Date:

14-Dec-2021

Product Category:

PoE PSE

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4611 Final Notice: Qualification of MMT as an additional assembly site for selected Microsemi PD69101ILQ-TR and PD69101ILQ-13155TR catalog part numbers (CPN) available in 24L VQFN (4x5x1.0mm) package.

Affected CPNs:

[JAON-23VTYQ024_Affected_CPN_12142021.pdf](#)

[JAON-23VTYQ024_Affected_CPN_12142021.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MMT as an additional assembly site for selected Microsemi PD69101ILQ-TR and PD69101ILQ-13155TR catalog part numbers (CPN) available in 24L VQFN (4x5x1.0mm) package.

Pre and Post Change Summary:

	Pre Change	Post Change
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Final PCN Issue Date									X							
Qual Report Availability													X			
Estimated Implementation Date									X							

Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

March 26, 2021: Issued initial notification.

November 10, 2021: Issued final notification.

December 14, 2021: Re-issued final notification. Updated the qualification report to Rev B.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

- [PCN_JAON-23VTYQ024_Qual_Report_RevB.pdf](#)
- [PCN_JAON-23VTYQ024_Pre_and_Post_Change_Summary.pdf](#)

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

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If you wish to receive Microchip PCNs via email please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to change your PCN profile, including opt out. please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

CCB 4611
Pre and Post Change Summary
PCN#: JAON-23VTYQ024



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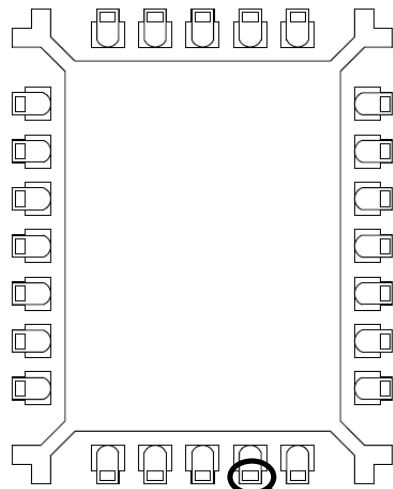


SMART | CONNECTED | SECURE

Lead Frame Comparison

NSEB

NSEB LF

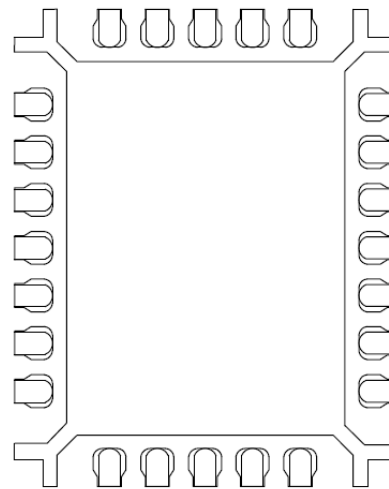


Lead lock hole

Lead frame material	EFTEC-64T
Lead frame Paddle size	114x154 mils
Lead-lock (Locking Hole)	Yes

UNIC

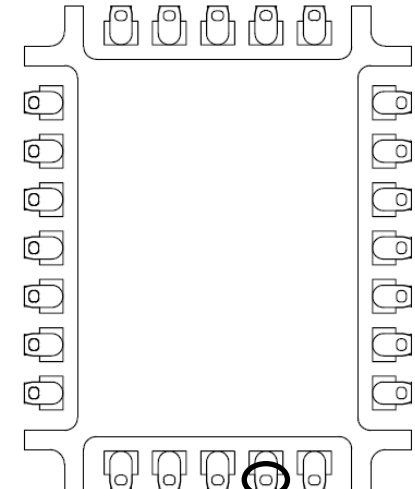
UNIC LF



Lead frame material	A194
Lead frame Paddle size	114x154 mils
Lead-lock (Locking Hole)	No

MMT

MMT LF



Lead lock hole

Lead frame material	A194
Lead frame Paddle size	114x154 mils
Lead-lock (Locking Hole)	Yes

Note: Mold compound material fills the leadlock hole, which provides improved protection against moisture penetration along the edge of the leads (pins) of the package.



MICROCHIP

**QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY**

PCN# JAON-23VTYQ024

Date

November 29, 2021

**Qualification of MMT as an additional assembly site for
selected Microsemi PD69101ILQ-TR and PD69101ILQ-13155TR
catalog part numbers (CPN) available in 24L VQFN (4x5x1.0mm)
package.**



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose	Qualification of MMT as an additional assembly site for selected Microsemi PD69101ILQ-TR and PD69101ILQ-13155TR catalog part numbers (CPN) available in 24L VQFN (4x5x1.0mm)
CN	ES355975
QUAL ID	R2100444 Rev B
MP CODE	U0151Q5FCA01
Part No.	PD69101ILQ-13155TR
Bonding No.	BDM-002819 Rev. B
CCB No.	4611
<u>Package</u>	
Type	24L VQFN
Package size	4 x 5 x 1.0 mm
<u>Lead Frame</u>	
Paddle size	114 x 154 mils
Material	A194
Surface	Bare Cu
Process	Etched
Lead Lock	Yes
Part Number	10102405
Treatment	BOT
<u>Material</u>	
Epoxy	3280
Wire	CuPdAu
Mold Compound	G700LTD
Plating Composition	Matte Sn



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-220300001.000	MC04921225644.100	2115RA4
MMT-220201309.000	MC04921215504.100	2114RA2
MMT-221001906.000	MC04921225677.100	2122AMG

Result

Pass Fail _____

24L VQFN (4x5x1.0 mm) assembled by MMT pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C
reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Moisture/Reflow Sensitivity Classification Test (At MSL Level 3)	30°C/ 60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020E)	IPC/JEDEC J-STD-020E	135	0/135	Pass	
Precondition Prior Perform Reliability Tests (At MSL Level 3)	<p>Electrical Test: +25°C and 85°C System: ETS</p> <p>Bake 150°C, 24 hrs System: CHINEE</p> <p>30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH</p> <p>3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243</p> <p>Electrical Test: +25°C and 85°C System: ETS</p>	JESD22A113	693(0)	<p>693</p> <p>693</p> <p>693</p> <p>693</p> <p>0/693</p>	<p></p> <p></p> <p></p> <p></p> <p>Pass</p>	<p>Good Devices</p>

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +25°C and 85°C System: ETS	JESD22-A104	231(0)	231	Pass	77 units
				0/231	Pass	Parts had been pre-conditioned at 260°C
	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +25°C and 85°C System: ETS		231	Pass		
	Bond Strength: Wire Pull (>4.00 grams) Bond Shear (>18.00 grams)		231(0)	0/231	Pass	
			15(0)	0/15	Pass	
			15(0)	0/15	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 57 Volts System: HAST 6000X	JESD22-A110		231		
	Electrical Test: +25°C and 85°C System: ETS		231(0)	0/231	Pass	77 units / lot
	Stress Condition: +130°C/85%RH, 192 hrs. Bias Volt: 57 Volts System: HAST 6000X			231		
	Electrical Test: +25°C and 85°C System: ETS		231(0)	0/231	Pass	77 units / lot
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: ETS		231(0)	0/231	Pass	77 units / lot
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			231		
	Electrical Test: +25°C System: ETS		231(0)	0/231	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB Electrical Test: +25°C and 85°C System: ETS	JESD22-A103	60(0)	60 60(0)	Pass	20 units / lot
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9Cu0.6 System: ERS A RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22(0)	22 22 0/22	Pass	
Wire sweep	Wire sweep Inspection 5 Wires / lot		45(0) Wires	0/45	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (>4.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass	
	Bond Shear (>18.00 grams)	CDF-AECQ100-001	30 (0) bonds	0/30	Pass	

Affected Catalog Part Numbers (CPN)

PD69101ILQ-TR

PD69101ILQ-13155TR